

Docket No.: 61282-048

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	Customer Number: 20277
	:	
Shinya TOKUNAGA, et al.	:	Confirmation Number:
	:	
Serial No.:	:	Group Art Unit:
	:	
Filed: November 26, 2003	:	Examiner:
	:	
For:		MASK PATTERN INSPECTING METHOD, INSPECTION APPARATUS, INSPECTING DATA USED THEREIN AND INSPECTING DATA GENERATING METHOD

INFORMATION DISCLOSURE STATEMENT

Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

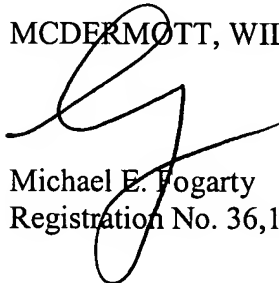
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Serial No.:

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

MCDERMOTT, WILL & EMERY

A handwritten signature in black ink, appearing to be 'M. Fogarty', written over the printed name.

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Date: November 26, 2003

INFORMATION DISCLOSURE CITATION IN AN APPLICATION						ATTY. DOCKET NO. 61282-048		SERIAL NO.	
(PTO-1449)						APPLICANT Shinya TOKUNAGA, et al.			
						FILING DATE November 26, 2003		GROUP	
U.S. PATENT DOCUMENTS									
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear				
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FOREIGN PATENT DOCUMENTS									
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes - Number - Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation			
						Yes	No		
		JP 2000-113189 (w/ English Abstract)	04/21/2000	TOSHIBA CORP.					
		JP 2002-196483 (w/ English Abstract)	07/12/2002	HITACHI LTD.					
		JP 2003-121983 (w/ English Abstract)	04/23/2003	DAIIPPON PRINTING CO., LTD.					
		JP 2002-258463 (w/ English Abstract)	09/11/2002	DAIIPPON PRINTING CO., LTD.					
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)									
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.							
EXAMINER				DATE CONSIDERED					

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.